

**Notice of References Cited**

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Applicant(s)/Patent Under  
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WEISS, STEVEN A.

Examiner

Kim Nguyen

Art Unit

3713

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,468,162	10-2002	Nakamura, Takashi	463/43
	B	US-6,450,884	09-2002	Seelig et al.	463/17
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	S					
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**NON-PATENT DOCUMENTS**

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